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Elektronikkomponenter – Långtidslagring av halvledarkomponenter – Del 1: Allmänt

*Electronic components –
Long-term storage of electronic semiconductor devices –
Part 1: General*

Som svensk standard gäller europastandarden EN 62435-1:2017. Den svenska standarden innehåller den officiella engelska språkversionen av EN 62435-1:2017.

Nationellt förord

Europastandarden EN 62435-1:2017

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English Version

**Electronic components - Long-term storage of electronic
semiconductor devices - Part 1: General
(IEC 62435-1:2017)**

Composants électroniques - Stockage de longue durée des
dispositifs électroniques à semiconducteurs -
Partie 1: Généralités
(IEC 62435-1:2017)

Elektronische Bauteile - Langzeitlagerung elektronischer
Halbleiterbauelemente - Teil 1: Allgemeines
(IEC 62435-1:2017)

This European Standard was approved by CENELEC on 2017-02-24. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 47/2326/FDIS, future edition 1 of IEC 62435-1, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62435-1:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-11-24
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-02-24

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Endorsement notice

The text of the International Standard IEC 62435-1:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-2-17:1994	NOTE	Harmonized as EN 60068-2-17:1994 (not modified).
IEC 60068-2-20:2008	NOTE	Harmonized as EN 60068-2-20:2008 (not modified).
IEC 60749-20-1	NOTE	Harmonized as EN 60749-20-1.
IEC 60749-21	NOTE	Harmonized as EN 60749-21.
IEC 61340-5-1:2007	NOTE	Harmonized as EN 61340-5-1:2007 (not modified).
IEC/TR 61340-5-2:2007	NOTE	Harmonized as CLC/TR 61340-5-2:2008 (not modified).
IEC 62258	NOTE	Harmonized in EN 62258 / CLC/TR 62258 series.
IEC/TR 62258-3	NOTE	Harmonized as CLC/TR 62258-3.
IEC 62402	NOTE	Harmonized as EN 62402.
IEC 62435-2	NOTE	Harmonized as EN 62435-2.
IEC 62435-5	NOTE	Harmonized as EN 62435-5.
ISO 14644	NOTE	Harmonized in EN ISO 14644 series.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-20-1	-	Semiconductor devices - Mechanical and climatic test methods - Part 20-1: Handling, packing, labelling and shipping of surface-mount devices sensitive to the combined effect of moisture and soldering heat	EN 60749-20-1	-

CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope.....	8
2 Normative references	8
3 Terms definitions and abbreviated terms	8
3.1 Terms and definitions.....	8
3.2 Abbreviations	9
4 Purpose of long-term storage	9
4.1 General.....	9
4.2 Storage decision criteria	10
4.2.1 Advantages	10
4.2.2 Hazards.....	10
4.2.3 Storage cost	11
4.2.4 Decision criteria.....	12
4.3 Reasons and methodology	12
4.4 Market forces	13
4.5 Risk mitigation and insurance	13
4.6 Obsolescence mitigation	13
5 Logistics.....	13
5.1 Procurement requirements.....	13
5.1.1 List of components	13
5.1.2 Quantity of components to be stored	14
5.1.3 When is it worth keeping in stock?.....	14
5.1.4 Procurement recommendations	14
5.2 Elementary storage unit	15
5.3 Stock management	15
5.4 Redundancy.....	15
5.5 Storage regimen	15
5.5.1 Storage concerns	15
5.5.2 Identification and traceability	15
5.6 Removal from storage.....	16
5.6.1 Precautions	16
5.6.2 Stock rotation	16
5.7 Periodic check of the components.....	16
5.7.1 General	16
5.7.2 Objectives	17
5.7.3 Periodicity	17
5.7.4 Tests during periodic check	17
6 Storage considerations for devices after card (or other) attachment.....	17
7 Handling.....	18
8 Inspection.....	18
9 Inventory control process.....	18
10 Transportation	18
11 Lead finishes	18
12 Kitting and lot control.....	18

13	Validation	19
14	Unplanned storage and types of storage.....	19
14.1	Types of storage	19
14.2	Unplanned storage.....	19
15	Other things to store in addition to the components	20
15.1	Relevant data	20
15.2	Equipment	20
16	Storage facility	20
16.1	Cost of ownership	20
16.2	Physical security and safety.....	20
16.3	Location and ambient environment.....	20
17	Policies	21
17.1	General.....	21
17.2	Supply chain	21
17.3	Re-starting the manufacturing chain.....	21
18	Legislation and environmental issues	21
	Annex A (informative) Example checklist for project managers	22
	Annex B (normative) Example checklist for long-term storage facilities	24
	Annex C (informative) Example of a component list	26
	C.1 Component list.....	26
	C.2 Data description.....	27
	Annex D (informative) Examples of periodic and/or de-stocking tests.....	28
	Annex E (informative) Parameters influencing the quantity of components to be stored	30
	Bibliography.....	31
	Table 1 – Storage hazards.....	11
	Table A.1 – Example checklist for project managers	22
	Table B.1 – Example checklist for storage facilities.....	24
	Table C.1 – Component list.....	26
	Table D.1 – Periodic and/or de-stocking tests	28

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTRONIC COMPONENTS –
LONG-TERM STORAGE OF ELECTRONIC
SEMICONDUCTOR DEVICES –**

Part 1: General

FOREWORD

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International Standard IEC 62435-1 has been prepared by IEC technical committee 47: Semiconductor devices.

This standard cancels and replaces IEC/PAS 62435 published in 2005. This first edition constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/2326/FDIS	47/2349/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62435 series, published under the general title *Electronic components – Long-term storage of electronic semiconductor devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

INTRODUCTION

This document applies to the long-term storage of electronic components.

This is a document for long-term storage (LTS) of electronic devices drawing on the best long-term storage practices currently known. For the purposes of this document, LTS is defined as any device storage whose duration can be more than 12 months for product scheduled for long duration storage. While intended to address the storage of unpackaged semiconductors and packaged electronic devices, nothing in this standard precludes the storage of other items under the storage levels defined herein.

Although it has always existed to some extent, obsolescence of electronic components and particularly of integrated circuits, has become increasingly intense over the last few years.

Indeed, with the existing technological boom, the commercial life of a component has become very short compared with the life of industrial equipment such as that encountered in the aeronautical field, the railway industry or the energy sector.

The many solutions enabling obsolescence to be resolved are now identified. However, selecting one of these solutions should be preceded by a case-by-case technical and economic feasibility study, depending on whether storage is envisaged for field service or production, for example:

- remedial storage as soon as components are no longer marketed;
- preventive storage anticipating declaration of obsolescence.

Taking into account the expected life of some installations, sometimes covering several decades, the qualification times, and the unavailability costs, which can also be very high, the solution to be adopted to resolve obsolescence should often be rapidly implemented. This is why the solution retained in most cases consists in systematically storing components which are in the process of becoming obsolescent.

The technical risks of this solution are, a priori, fairly low. However, it requires perfect mastery of the implemented process and especially of the storage environment, although this mastery becomes critical when it comes to long-term storage.

All handling, protection, storage and test operations are recommended to be performed according to the state of the art.

The application of the approach proposed in this standard in no way guarantees that the stored components are in perfect operating condition at the end of this storage. It only comprises a means of minimizing potential and probable degradation factors.

Some electronic device users have the need to store electronic devices for long periods of time. Lifetime buys are commonly made to support production runs of assemblies that will exceed the production timeframe of its individual parts. This puts the user in a situation requiring careful and adequate storage of such parts to maintain the as-received solderability and minimize any degradation effects to the part over time. Major degradation concerns are moisture, electrostatic fields, ultra-violet light, large variations in temperature, air-borne contaminants, and outgassing.

Warranties and sparring also present a challenge for the user or repair agency as some systems have been designated to be used for long periods of time, in some cases for up to 40 years or more. Some of the devices needed for repair of these systems will not be available from the original supplier for the lifetime of the system or the spare assembly may be built with the original production run but then require long-term storage. This document was developed to provide a standard for storing electronic devices for long periods of time.

For storage of devices that are moisture sensitive but that do not need to be stored for long periods of time, refer to IEC TR 62258-3.

Long-term storage assumes that the device is going to be placed in uninterrupted storage for a number of years. It is essential that it is useable after storage. Particular attention should be paid to storage media surrounding the devices together with the local environment.

These guidelines do not imply any warranty of product or guarantee of operation beyond the storage time given by the manufacturer.

The IEC 62435 series is intended to ensure that adequate reliability is achieved for devices in user applications after long-term storage. Users are encouraged to request data from suppliers to applicable specifications to demonstrate a successful storage life as requested by the user. These standards are not intended to address built-in failure mechanisms that would take place regardless of storage conditions.

These standards are intended to give practical guide to methods of long-duration storage of electronic components where this is intentional or planned storage of product for a number of years. Storage regimes for work-in-progress production are managed according to company internal process requirements and are not detailed in this series of standards.

The overall standard is split into a number of parts. Parts 1 to 4 apply to any long-term storage and contain general requirements and guidance, whereas Parts 5 to 9¹ are specific to the type of product being stored. It is intended that the product specific part should be read alongside the general requirements of Parts 1 to 4.

Electronic components requiring different storage conditions are covered separately starting with Part 5.

The structure of the IEC 62435 series as currently conceived is as follows:

Part 1 – General

Part 2 – Deterioration mechanisms

Part 3 – Data

Part 4 – Storage

Part 5 – Die and wafer devices

Part 6 – Packaged or finished devices

Part 7 – MEMS

Part 8 – Passive electronic devices

Part 9 – Special cases

¹ Under preparation.

ELECTRONIC COMPONENTS – LONG-TERM STORAGE OF ELECTRONIC SEMICONDUCTOR DEVICES –

Part 1: General

1 Scope

This part of IEC 62435 on long-term-storage covers the terms, definitions and principles of long-term-storage that can be used in as an obsolescence mitigation strategy. Long-term storage refers to a duration that can be more than 12 months for products scheduled for long duration storage. Philosophy, good working practice, and general means to facilitate the successful long-term-storage of electronic components are also addressed.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60749-20-1, *Semiconductor devices – Mechanical and climatic test methods – Part 20-1: Handling, packing, labelling and shipping of surface-mount devices sensitive to the combined effect of moisture and soldering heat*